The attached figures may be found helpful for those defining and using the SPM terms.

- Fig 1 provides a family tree for SPM methods.
- Figs 2 and 3 illustrate complex probes.
- Fig 4 shows the probe assembly and chip carrier.

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Fig 1 - Family tree for the SPM Methods

Fig 1 - Family tree for the SPM Methods (yellow terms defined)
Fig 2 - Basic and more complex cantilevers, e.g. nanotube on standard mount – The "cantilever assembly"

If the probe designed to interrogate the surface is mounted on a regular tip, then the regular tip becomes the "probe support" and all terms that would normally be attributed to the regular tip are transferred to the new probe. The terms in bold italics are defined.
Fig 3 – A typical complex FIB machined cantilever.

Fig 2 exampled a composite tip based on a carbon nanotube probe supported by a regular tip but a composite probe may also be FIB machined from a single material as shown schematically below left. There are also tilt-compensated probes, as shown right, where we define the probe tilt angle.
Fig 4 – The complete probe assembly

The cantilever assembly may be mounted on a chip holder to make up the complete probe assembly.